

**IDT54/74FCT191T/AT**

- Std. and A speed grades
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- High drive outputs (-15mA I_{OH} , 48mA I_{OL})
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Military product compliant to MIL-STD-883, Class B and DESC listed (dual marked)
- Available in DIP, SOIC, CERPACK and LCC packages

The IDT54/74FCT191T and IDT54/74FCT191AT are reversible modulo-16 binary counters, featuring synchronous counting and asynchronous presetting and are built using an advanced dual metal CMOS technology. The preset feature allows the IDT54/74FCT191T and IDT54/74FCT191AT to be used in programmable dividers. The count enable input, terminal count output and ripple clock output make possible a variety of methods of implementing multiusage counters. In the counting modes, state changes are initiated by the rising edge of the clock.

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MILITARY AND COMMERCIAL TEMPERATURE RANGES

MARCH 1994

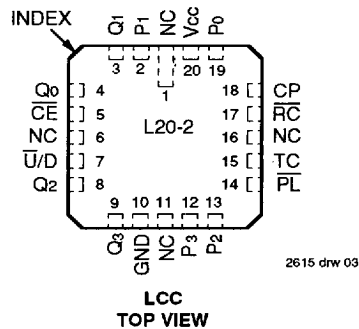
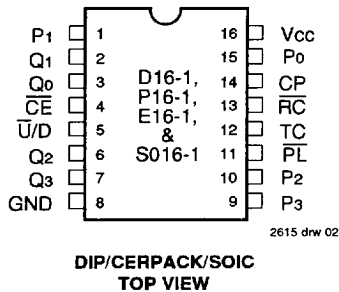
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DSC-4207/3

4825771 0015640 5TB

PIN CONFIGURATIONS



PIN DESCRIPTION

Pin Names	Description
$\overline{CE}$	Count Enable Input (Active LOW)
CP	Clock Pulse Input (Active Rising Edge)
P0-3	Parallel Data Inputs
$\overline{PL}$	Asynchronous Parallel Load Input (Active LOW)
$\overline{U/D}$	Up/Down Count Control Input
Q0-3	Flip-Flop Outputs
$\overline{RC}$	Ripple Clock Output (Active LOW)
TC	Terminal Count Output (Active HIGH)

2615 tbl 01

$\overline{RC}$ FUNCTION TABLE⁽²⁾

Inputs		Outputs	
$\overline{CE}$	CP	TC ⁽¹⁾	$\overline{RC}$
L		H	
H	X	X	H
X	X	L	H

2615 tbl 02

MODE SELECT FUNCTION TABLE⁽²⁾

Inputs				Mode
PL	$\overline{CE}$	$\overline{U/D}$	CP	
H	L	L	$\uparrow$	Count Up
H	L	H	$\uparrow$	Count Down
L	X	X	X	Preset (Asynchronous)
H	H	X	X	No Change (Hold)

- NOTES:**
- TC is generated internally
 - H = HIGH Voltage Level, L = LOW Voltage Level, X = Don't Care, $\uparrow$ = LOW-to-HIGH clock transition.

2615 tbl 03

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Military	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to V _{CC} + 0.5	-0.5 to V _{CC} + 0.5	V
T _A	Operating Temperature	0 to +70	-55 to +125	°C
T _{BIAS}	Temperature Under Bias	-55 to +125	-65 to +135	°C
T _{STG}	Storage Temperature	-55 to +125	-65 to +150	°C
P _T	Power Dissipation	0.5	0.5	W
I _{OUT}	DC Output Current	-60 to +120	-60 to +120	mA

NOTES: 2615 lmk 04

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Input and V_{CC} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

NOTE:

2615 lmk 05

- This parameter is measured at characterization but not tested.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: T_A = 0°C to +70°C, V_{CC} = 5.0V ± 5%; Military: T_A = -55°C to +125°C, V_{CC} = 5.0V ± 10%

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V _{IH}	Input HIGH Level	Guaranteed Logic HIGH Level	COM'L. ⁽⁵⁾	2.0	—	—	V
			MIL.	2.7	—	—	V
V _{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I _{IH}	Input HIGH Current ⁽⁴⁾	V _{CC} = Max.	V _I = 2.7V	—	—	±1	μA
I _{IL}	Input LOW Current ⁽⁴⁾		V _I = 0.5V	—	—	±1	μA
I _{OZH}	High Impedance Output Current	V _{CC} = Max.	V _O = 2.7V	—	—	±1	μA
I _{OZL}	(3-State Output pins) ⁽⁴⁾		V _O = 0.5V	—	—	±1	μA
I _I	Input HIGH Current ⁽⁴⁾	V _{CC} = Max., V _I = V _{CC} (Max.)		—	—	±1	μA
V _{IK}	Clamp Diode Voltage	V _{CC} = Min., I _{IN} = -18mA		—	-0.7	-1.2	V
I _{OS}	Short Circuit Current	V _{CC} = Max., V _O = GND ⁽³⁾		-60	-120	-225	mA
V _{OH}	Output HIGH Voltage	V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OH} = -6mA MIL.	2.4	3.3	—	V
			I _{OH} = -8mA COM'L.				
			I _{OH} = -12mA MIL.	2.0	3.0	—	V
			I _{OH} = -15mA COM'L.				
V _{OL}	Output LOW Voltage	V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 32mA MIL.	—	0.3	0.5	V
			I _{OL} = 48mA COM'L.				
V _H	Input Hysteresis	—		—	200	—	mV
I _{CC}	Quiescent Power Supply Current	V _{CC} = Max., V _{IN} = GND or V _{CC}		—	0.01	1	mA

NOTES: 2615 lmk 06

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 5.0V, +25°C ambient.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- The test limit for this parameter is ±5μA at T_A = -55°C.
- Clock pin requires a minimum V_{IH} of 2.5V.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2.0	μA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$, Outputs Open Preset Mode $PL = CE = \bar{U}/D = CP = GND$ One Bit Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = GND$	—	0.15	0.25	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$, Outputs Open Preset Mode $PL = CE = \bar{U}/D = CP = GND$ One Bit Toggling at $f_i = 5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = GND$	—	0.8	2.3	mA
			$V_{IN} = 3.4V$ $V_{IN} = GND$	—	1.0	3.3	
		$V_{CC} = \text{Max.}$, Outputs Open Preset Mode $PL = CE = \bar{U}/D = CP = GND$ Four Bits Toggling at $f_i = 5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = GND$	—	3.0	6.0 ⁽⁵⁾	
			$V_{IN} = 3.4V$ $V_{IN} = GND$	—	4.0	10.0 ⁽⁵⁾	

NOTES:

2615 tbl 09

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ C$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CC} + \Delta I_{CC} DH/N_T + I_{CCD} (f_{CP}/2 + f_i N_i)$
 $I_{CC} = \text{Quiescent Current}$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$
 $DH = \text{Duty Cycle for TTL Inputs High}$
 $N_T = \text{Number of TTL Inputs at } DH$
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$
 $f_i = \text{Input Frequency}$
 $N_i = \text{Number of Inputs at } f_i$
 All currents are in milliamperes and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Condition ⁽¹⁾	FCT191T				FCT191AT				Unit
			Com'l.		Mil.		Com'l.		Mil.		
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
tPLH tPHL	Propagation Delay CP to Q _n	CL = 50pF RL = 500Ω	2.5	12.0	1.5	16.0	2.5	7.8	1.5	10.5	ns
tPLH tPHL	Propagation Delay CP to TC		3.0	14.0	2.0	16.0	3.0	11.8	2.0	12.2	ns
tPLH tPHL	Propagation Delay CP to RC		2.5	8.5	1.5	12.5	2.5	8.5	1.5	10.0	ns
tPLH tPHL	Propagation Delay CE to RC		2.0	8.0	2.0	8.5	2.0	7.2	2.0	8.0	ns
tPLH tPHL	Propagation Delay U/D to RC		4.0	20.0	4.0	22.5	4.0	13.0	4.0	14.7	ns
tPLH tPHL	Propagation Delay U/D to TC		3.0	11.0	3.0	13.0	3.0	7.2	3.0	8.5	ns
tPLH tPHL	Propagation Delay P _n to Q _n		2.0	14.0	1.5	16.0	2.0	9.1	1.5	10.4	ns
tPLH tPHL	Propagation Delay PL to Q _n		3.0	13.0	3.0	14.0	3.0	8.5	3.0	9.1	ns
tsu	Set-up Time, HIGH or LOW P _n to PL		5.0	—	6.0	—	4.0	—	5.0	—	ns
th	Hold Time, HIGH or LOW P _n to PL		1.5	—	1.5	—	1.5	—	1.5	—	ns
tsu	Set-up Time LOW CE to CP		10.0	—	10.5	—	9.0	—	9.5	—	ns
th	Hold Time LOW CE to CP		0	—	0	—	0	—	0	—	ns
tsu	Set-up Time, HIGH or LOW U/D to CP		12.0	—	12.0	—	10.0	—	10.0	—	ns
th	Hold Time, HIGH or LOW U/D to CP		0	—	0	—	0	—	0	—	ns
tw	PL Pulse Width LOW		6.0	—	8.5	—	5.5	—	8.0	—	ns
tw	Clock Pulse Width HIGH or LOW	5.0	—	7.0	—	4.0 ⁽³⁾	—	6.0	—	ns	
tREM	Recovery Time PL to CP	6.0	—	7.5	—	5.0	—	6.5	—	ns	

NOTES:

- See test circuit and waveform.
- Minimum limits are guaranteed but not tested on Propagation Delays.
- This limit is guaranteed but not tested.

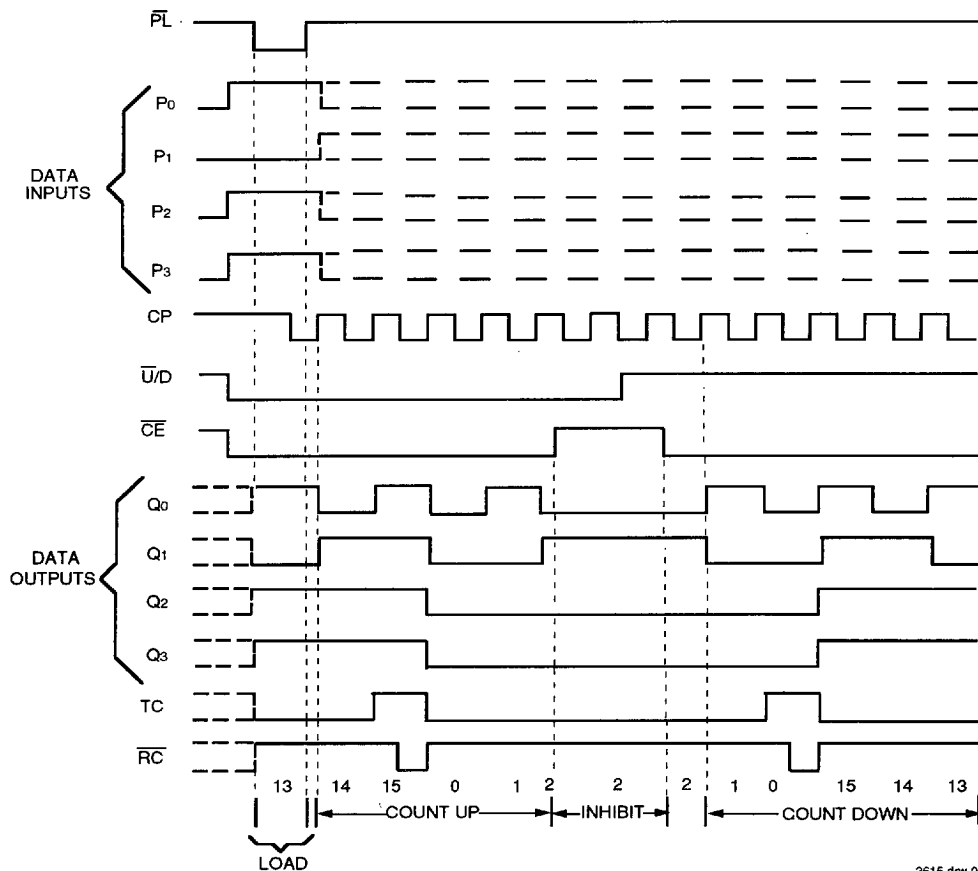
2615 tbl 09

TIMING WAVEFORMS

Typical load, count and inhibit sequences

Illustrated below is the following sequence:

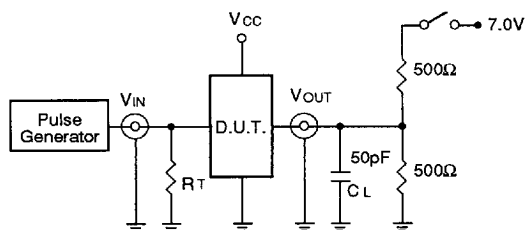
- Load (preset) to binary thirteen
- Count up to fourteen, fifteen (maximum), zero, one and two
- Inhibit
- Count down to one, zero (minimum), fifteen, fourteen and thirteen



2615 drw 04

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



2615 drw 05

SWITCH POSITION

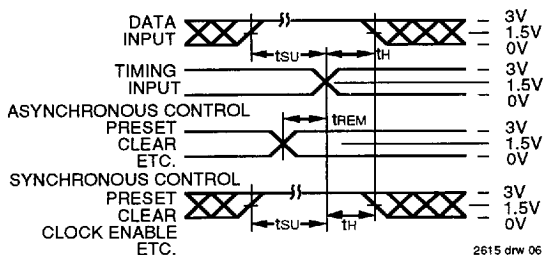
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

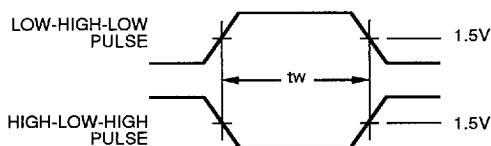
RT = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

SET-UP, HOLD AND RELEASE TIMES



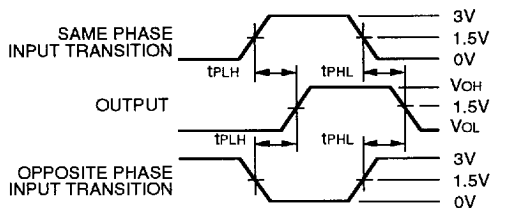
2615 drw 06

PULSE WIDTH



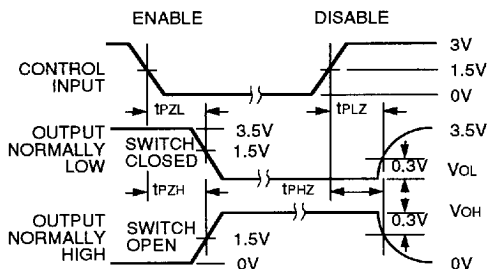
2615 drw 07

PROPAGATION DELAY



2615 drw 08

ENABLE AND DISABLE TIMES

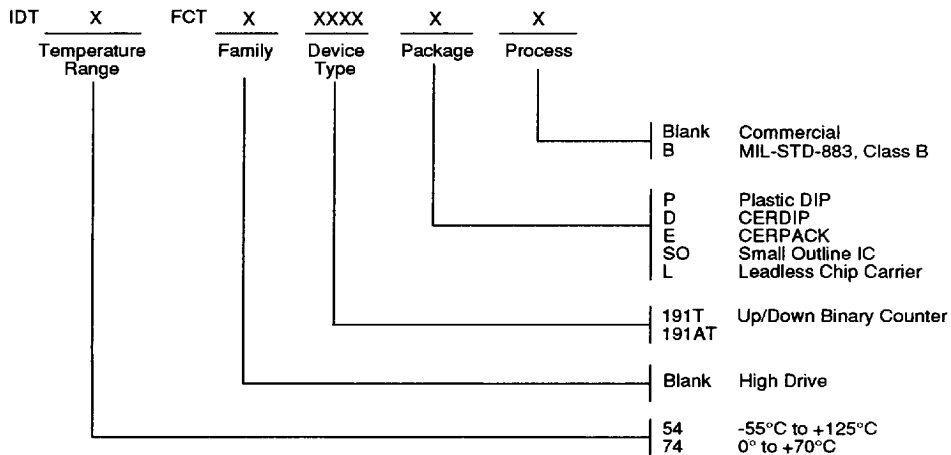


2615 drw 09

NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_r \leq 2.5\text{ns}$; $t_f \leq 2.5\text{ns}$

ORDERING INFORMATION



2615 drw 10